

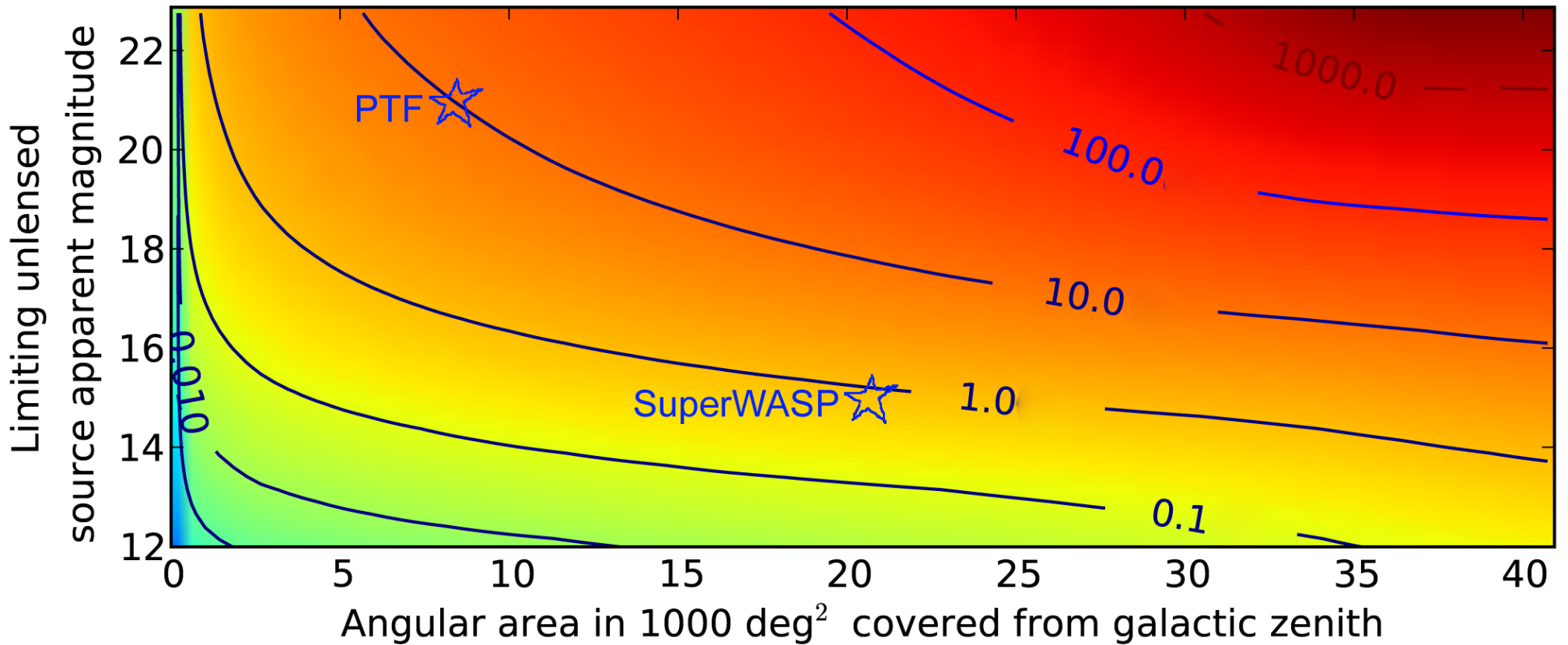
Predicting Field Microlensing Rates in Wide-Field Surveys

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Lower limit survey yield chart



Labelled contours represent lines of constant event rate in events per year.